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- ☐ 1. **Measuring phase noise at K-hand**
Key-Bolotin, J.A.; Chut-San Tsang;
Aerospace Conference, 1999. Proceedings. 1999 IEEE
Volume 5, 6-13 March 1999 Page(s):193 - 209 vol.5
[AbstractPlus](#) | Full Text: [PDF](#)(868 KB) IEEE CNF
- ☐ 2. **Phase noise measurement of free-running VCO using spectrum analyzer**
Chung Ming Yuen; Kim Fung Tsang;
Radio and Wireless Conference, 2004 IEEE
19-22 Sept. 2004 Page(s):443 - 446
[AbstractPlus](#) | Full Text: [PDF](#)(535 KB) IEEE CNF
- ☐ 3. **How to use a spectrum analyzer to measure phase noise of digital signal generat**
Zhan Zhiqiang;
Radio Science Conference, 2004. Proceedings. 2004 Asia-Pacific
24-27 Aug. 2004 Page(s):128 - 130
[AbstractPlus](#) | Full Text: [PDF](#)(1780 KB) IEEE CNF
- ☐ 4. **Using digital data processing to speed up radar phase noise measurements**
Guhse, D.; Luster, B.; Prcic, M.;
AUTOTESTCON '94. IEEE Systems Readiness Technology Conference. 'Cost Effectiv
Next Century', Conference Proceedings.
20-22 Sept. 1994 Page(s):205 - 210
[AbstractPlus](#) | Full Text: [PDF](#)(600 KB) IEEE CNF
- ☐ 5. **Phase noise measurement of free-running microwave oscillators at 5.8 GHz usin**
subharmonic Injection locking
Kim Fung Tsang; Chung Ming Yuen;
Microwave and Wireless Components Letters, IEEE [see also IEEE Microwave and Gu
Letters]
Volume 15, Issue 4, April 2005 Page(s):217 - 219
[AbstractPlus](#) | Full Text: [PDF](#)(128 KB) IEEE JNL
- ☐ 6. **A frequency conversion scheme for an advanced portable microwave spectrum :**
Hill, T.; Lockwood, L.;
Microwave Symposium Digest, 1990., IEEE MTT-S International
8-10 May 1990 Page(s):447 - 450 vol.1

[AbstractPlus](#) | Full Text: [PDF](#)(200 KB) IEEE CNF

- ☐ 7. **The Influence of transistor nonlinearities on noise properties**
Sungjae Lee; Webb, K.J.;
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Volume 53, Issue 4, April 2005 Page(s):1314 - 1321
[AbstractPlus](#) | Full Text: [PDF](#)(432 KB) IEEE JNL
- ☐ 8. **MOSFET 1/f noise measurement under switched bias conditions**
Zhang, C.W.; Louie, M.Y.; Forbes, L.;
Microelectronics and Electron Devices, 2004 IEEE Workshop on
2004 Page(s):79 - 81
[AbstractPlus](#) | Full Text: [PDF](#)(1435 KB) IEEE CNF
- ☐ 9. **Automated phase noise measurement of Ku-band MMIC VCO on-wafer**
Yang, J.M.; Yang, D.C.; Cheng, P.G.; Dickson, J.M.;
Microwave Symposium Digest, 1999 IEEE MTT-S International
Volume 4, 13-19 June 1999 Page(s):1763 - 1766 vol.4
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- ☐ 10. **Phase noise measurements of a double-locked laser diode**
Simpson, T.B.; Doft, F.; Shin, D.S.; Yu, P.K.L.;
Lasers and Electro-Optics Society, 2001. LEOS 2001. The 14th Annual Meeting of the
Volume 1, 12-13 Nov. 2001 Page(s):117 - 118 vol.1
[AbstractPlus](#) | Full Text: [PDF](#)(155 KB) IEEE CNF
- ☐ 11. **Phase noise in surface-acoustic-wave filters and resonators**
Baer, R.L.;
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Volume 35, Issue 3, May 1988 Page(s):421 - 425
[AbstractPlus](#) | Full Text: [PDF](#)(372 KB) IEEE JNL
- ☐ 12. **Noise characterisation of mode-locked laser sources using high-speed InGaAs p**
Finch, A.; Burns, D.; Zhu, X.N.; Sleat, W.E.; Sibbett, W.;
Applications of Ultrashort Pulses for Optoelectronics, IEE Colloquium on
26 May 1989 Page(s):8/1 - 8/4
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- ☐ 13. **YBCO shielded LaAlO/sub 3/ dielectric resonators for stable oscillators**
Klein, N.; Tellmann, N.; Dahne, T.; Scholen, A.; Schulz, H.; Hofer, G.; Kratz, H.;
Applied Superconductivity, IEEE Transactions on
Volume 5, Issue 2, Jun 1995 Page(s):2663 - 2666
[AbstractPlus](#) | Full Text: [PDF](#)(312 KB) IEEE JNL
- ☐ 14. **A 2.5-GHz eight-phase VCO in SiGe BiCMOS technology**
Herzel, F.; Winkler, W.;
Circuits and Systems II: Express Briefs, IEEE Transactions on [see also Circuits and S
and Digital Signal Processing, IEEE Transactions on]
Volume 52, Issue 3, March 2005 Page(s):140 - 144
[AbstractPlus](#) | Full Text: [PDF](#)(224 KB) IEEE JNL
- ☐ 15. **Increasing dynamic range of practical microwave spectrum analysis by reducing compensating system noise**
Lipovac, V.; Honisch, W.;
Microwave and Optoelectronics Conference, 2003. IMOC 2003. Proceedings of the 20
MTT-S International
Volume 2, 20-23 Sept. 2003 Page(s):1069 - 1073 vol.2

[AbstractPlus](#) | Full Text: [PDF](#)(338 KB) [IEEE CNF](#)

- ☐ **16. The influence of transistor nonlinearities on intrinsic noise**
Sungjae Lee; Webb, K.J.; Eastman, L.F.;
Microwave Symposium Digest, 2004 IEEE MTT-S International
Volume 3, 6-11 June 2004 Page(s):1867 - 1870 Vol.3
[AbstractPlus](#) | Full Text: [PDF](#)(490 KB) [IEEE CNF](#)
- ☐ **17. Extending the range for precision AM noise measurements**
Nelson, C.W.; Walls, F.L.; Boggs, C.K.;
Frequency Control Symposium, 1996. 50th., Proceedings of the 1996 IEEE International
5-7 June 1996 Page(s):854 - 857
[AbstractPlus](#) | Full Text: [PDF](#)(484 KB) [IEEE CNF](#)
- ☐ **18. Noise in mixers, oscillators, samplers, and logic an Introduction to cyclostationa**
Phillips, J.; Kundert, K.;
Custom Integrated Circuits Conference, 2000. CICC. Proceedings of the IEEE 2000
21-24 May 2000 Page(s):431 - 438
[AbstractPlus](#) | Full Text: [PDF](#)(768 KB) [IEEE CNF](#)
- ☐ **19. Automated Spectral Analysis of Microwave Oscillator Noise**
Ashley, J.R.; Barley, T.A., Jr.; Rast, G.J.;
Microwave Symposium Digest, MTT-S International
Volume 76, Issue 1, Jun 1976 Page(s):227 - 229
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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L4	290	(spectrum adj2 analyzer) and (phase adj2 noise)	USPAT	OR	ON	2005/06/28 11:08
L5	958	model same phase same noise	USPAT	OR	ON	2005/06/28 11:04
L6	25	4 and 5	USPAT	OR	ON	2005/06/28 11:05
L7	0	("6621277").URPN.	USPAT	OR	ON	2005/06/28 11:08
L8	68	(spectrum adj2 analyzer) same (phase adj2 noise)	USPAT	OR	ON	2005/06/28 11:11
L9	4	(spectrum adj2 analyzer) and (phase adj2 noise adj2 model)	USPAT	OR	ON	2005/06/28 11:25
L10	9	internal adj2 phase adj2 noise	USPAT	OR	ON	2005/06/28 11:27
L11	97	phase adj2 noise adj2 cancel\$5	USPAT	OR	ON	2005/06/28 11:28
L12	6	11 and (spectrum adj2 analyzer)	USPAT	OR	ON	2005/06/28 11:27
L13	0	(phase adj2 noise adj2 cancel\$5) same internal	USPAT	OR	ON	2005/06/28 11:28
L14	75	(phase same noise same cancel\$7) same internal	USPAT	OR	ON	2005/06/28 11:33
L15	6278	vna or (spectrum adj2 analyzer)	USPAT	OR	ON	2005/06/28 11:33
L16	4933	phase adj2 noise	USPAT	OR	ON	2005/06/28 11:33
L17	292	15 and 16	USPAT	OR	ON	2005/06/28 11:33
L18	4	17 and (internal same cancel\$7)	USPAT	OR	ON	2005/06/28 11:33
L19	6	("5172064").URPN.	USPAT	OR	ON	2005/06/28 11:46
L20	10	(sideband adj2 noise) same cancel\$5	USPAT	OR	ON	2005/06/28 12:31
L21	45	internal same (noise or jitter) same spectrum same analyzer	USPAT	OR	ON	2005/06/28 12:35
L22	83	phase same noise same measurement same spectrum same analyzer	USPAT	OR	ON	2005/06/28 12:40
L23	20290	"702"/\$.ccls.	USPAT	OR	ON	2005/06/28 14:36
L24	123	23 and (phase adj2 noise)	USPAT	OR	ON	2005/06/28 12:51
L25	1	"6730484".pn.	USPAT	OR	ON	2005/06/28 12:52
L26	1	"6370484".pn.	USPAT	OR	ON	2005/06/28 12:53
L27	1	"6335615".pn.	USPAT	OR	ON	2005/06/28 13:04
L28	2	("5337014" or "6313619").pn.	USPAT	OR	ON	2005/06/28 13:04
L29	659	702/111,106,107,69,72.ccls.	US-PGPUB; USPAT	OR	ON	2005/06/28 14:37
L30	914	331/18,19,44.ccls.	US-PGPUB; USPAT	OR	ON	2005/06/28 14:37
L31	1056	324/613,614,615,617,620,624,622,76.19,76.22.ccls.	US-PGPUB; USPAT	OR	ON	2005/06/28 14:37

L32	1032	375/224,226,227.ccls.	US-PGPUB; USPAT	OR	ON	2005/06/28 14:37
L33	3555	29 or 30 or 31 or 32	US-PGPUB; USPAT	OR	ON	2005/06/28 14:37

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Most Frequently Occurring Classifications of Patents Returned
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Original Classifications

7 324/613
2 324/76.27
2 331/2
2 342/135

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Cross-Reference Classifications

4 324/76.23
3 324/76.27
3 331/25
3 342/145
2 324/622
2 324/76.17
2 324/76.26
2 324/76.29
2 324/76.43
2 324/77.11
2 324/84
2 324/85
2 327/100
2 331/11
2 331/14
2 331/16
2 331/179
2 455/226.1
2 455/67.13
2 455/67.16
2 455/76
2 702/106
2 708/309
2 708/422

Combined Classifications

7 324/613
5 324/76.23
5 324/76.27
3 331/2
3 331/25
3 342/145
2 324/622
2 324/76.17
2 324/76.19
2 324/76.26
2 324/76.29
2 324/76.43
2 324/77.11
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2 327/100
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2 331/16
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2 455/67.16
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2 702/106
2 702/76
2 708/309
2 708/422

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- 7 324/613 (7 OR, 0 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
RELATIONSHIPS
324/612 .Parameter related to the reproduction or
fidelity of a signal affected by a circuit under test
324/613 ..Noise
- 5 324/76.23 (1 OR, 4 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
SE
324/76.12 .Analysis of complex waves
324/76.19 ..Frequency spectrum analyzer
324/76.23 ...With mixer
- 5 324/76.27 (2 OR, 3 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
SE
324/76.12 .Analysis of complex waves
324/76.19 ..Frequency spectrum analyzer
324/76.26 ...Scanning-panoramic receiver
324/76.27With particular sweep circuit
- 3 331/2 (2 OR, 1 XR)
Class 331 : OSCILLATORS
331/1R AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
OR FREQUENCY SENSING MEANS
331/2 .Plural oscillators controlled
- 3 331/25 (0 OR, 3 XR)
Class 331 : OSCILLATORS
331/1R AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
OR FREQUENCY SENSING MEANS
331/18 .with reference oscillator or source
331/25 ..Signal or phase comparator
- 3 342/145 (0 OR, 3 XR)
Class 342 : COMMUNICATIONS: DIRECTIVE RADIO WAVE SYSTEMS
AND DEVICES
342/118 DETERMINING DISTANCE
342/145 .With correlation
- 2 324/622 (0 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
RELATIONSHIPS
324/612 .Parameter related to the reproduction or
fidelity of a signal affected by a circuit under test
324/620 ..Distortion
324/622 ...Phase
- 2 324/76.17 (0 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
SE

- 324/76.12 .Analysis of complex waves
 324/76.13 ..Amplitude distribution
 324/76.17 ...With integrator
- 2 324/76.19 (1 OR, 1 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
 SE
 324/76.12 .Analysis of complex waves
 324/76.19 ..Frequency spectrum analyzer
- 2 324/76.26 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
 SE
 324/76.12 .Analysis of complex waves
 324/76.19 ..Frequency spectrum analyzer
 324/76.26 ...Scanning-panoramic receiver
- 2 324/76.29 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
 SE
 324/76.12 .Analysis of complex waves
 324/76.19 ..Frequency spectrum analyzer
 324/77.11 ...Nonscanning
 324/76.29With filtering
- 2 324/76.43 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
 SE
 324/76.39 .Frequency of cyclic current or voltage (e.g.,
 cyclic counting etc.)
 324/76.41 ..Frequency comparison, (e.g., heterodyne,
 etc.)
 324/76.43 ...With plural mixers
- 2 324/77.11 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
 SE
 324/76.12 .Analysis of complex waves
 324/76.19 ..Frequency spectrum analyzer
 324/77.11 ...Nonscanning
- 2 324/84 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
 SE
 324/76.77 .Phase comparison (e.g., between cyclic pulse
 voltage and sinusoidal current, etc.)
 324/84 ..With waveguide (e.g., coaxial cable)
- 2 324/85 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
 SE
 324/76.77 .Phase comparison (e.g., between cyclic pulse
 voltage and sinusoidal current, etc.)
 324/85 ..With frequency conversion
- 2 327/100 (0 OR, 2 XR)

- Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
DEVICES, CIRCUITS, AND SYSTEMS
327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING
- 2 327/105 (1 OR, 1 XR)
Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
DEVICES, CIRCUITS, AND SYSTEMS
327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING
327/105 .Synthesizer
- 2 331/11 (0 OR, 2 XR)
Class 331 : OSCILLATORS
331/1R AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
OR FREQUENCY SENSING MEANS
331/10 .Plural A.F.S. for a single oscillator
331/11 ..Plural comparators or discriminators
- 2 331/14 (0 OR, 2 XR)
Class 331 : OSCILLATORS
331/1R AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
OR FREQUENCY SENSING MEANS
331/14 .With intermittent comparison controls
- 2 331/16 (0 OR, 2 XR)
Class 331 : OSCILLATORS
331/1R AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
OR FREQUENCY SENSING MEANS
331/16 .Tuning compensation
- 2 331/179 (0 OR, 2 XR)
Class 331 : OSCILLATORS
331/177R WITH FREQUENCY ADJUSTING MEANS
331/179 .Step-frequency change (e.g., band selection,
frequency-shift keying)
- 2 331/19 (1 OR, 1 XR)
Class 331 : OSCILLATORS
331/1R AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
OR FREQUENCY SENSING MEANS
331/18 .With reference oscillator or source
331/19 ..Spectrum reference source
- 2 342/135 (2 OR, 0 XR)
Class 342 : COMMUNICATIONS: DIRECTIVE RADIO WAVE SYSTEMS
AND DEVICES
342/118 DETERMINING DISTANCE
342/134 .With pulse modulation
342/135 ..Digital (e.g., with counter)
- 2 342/192 (1 OR, 1 XR)
Class 342 : COMMUNICATIONS: DIRECTIVE RADIO WAVE SYSTEMS
AND DEVICES
342/175 WITH PARTICULAR CIRCUIT
342/192 .Spectrum analysis
- 2 455/226.1 (0 OR, 2 XR)
Class 455 : TELECOMMUNICATIONS
455/130 RECEIVER OR ANALOG MODULATED SIGNAL FREQUENCY
CONVERTER
455/226.1 .Measuring or testing of receiver
- 2 455/67.13 (0 OR, 2 XR)
Class 455 : TELECOMMUNICATIONS

- 455/39 TRANSMITTER AND RECEIVER AT SEPARATE STATIONS
- 455/67.11 .Having measuring, testing, or monitoring of
system or part
- 455/67.13 ..Noise, distortion, or unwanted signal
detection (e.g., quality control, etc.)
- 2 455/67.16 (0 OR, 2 XR)
Class 455 : TELECOMMUNICATIONS
455/39 TRANSMITTER AND RECEIVER AT SEPARATE STATIONS
- 455/67.11 .Having measuring, testing, or monitoring of
system or part
- 455/67.16 ..Phase measuring (e.g., group delay,
propagation effect, etc.)
- 2 455/76 (0 OR, 2 XR)
Class 455 : TELECOMMUNICATIONS
455/73 TRANSMITTER AND RECEIVER AT SAME STATION (E.G.,
TRANSCEIVER)
- 455/75 .With frequency stabilization (e.g., automatic
frequency control)
- 455/76 ..Synthesizer
- 2 702/106 (0 OR, 2 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/85 CALIBRATION OR CORRECTION SYSTEM
702/106 .Signal frequency or phase correction
- 2 702/76 (1 OR, 1 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
702/57 .Electrical signal parameter measurement system
- 702/66 ..Waveform analysis
702/75 ...Frequency
702/76Frequency spectrum
- 2 708/309 (0 OR, 2 XR)
Class 708 : ELECTRICAL COMPUTERS: ARITHMETIC PROCESSING
AND CALCULATING
708/100 ELECTRICAL DIGITAL CALCULATING COMPUTER
708/200 .Particular function performed
708/300 ..Filtering
708/309 ...Frequency measurement
- 2 708/422 (0 OR, 2 XR)
Class 708 : ELECTRICAL COMPUTERS: ARITHMETIC PROCESSING
AND CALCULATING
708/100 ELECTRICAL DIGITAL CALCULATING COMPUTER
708/200 .Particular function performed
708/422 ..Correlation

PLUS Search Results for S/N 10807205, Searched June 28, 2005

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